



- **Isolated Mounting Base**  
makes your mechanical design easy.
- **High Reliable Glass Passivated Chips.**  
makes your system stable and reliable.
- **V<sub>DRM</sub> up to 1,600V**  
enables you to complete your system for the line voltage up to 400V.
- **High temperature Capability**  
enables you to get high-power.

■ SanRex Power Semiconductor PK-G,H Series

| Conection  | (V) |      |     |      |      |
|--|-----|------|-----|------|------|
|  | (A) | 400  | 800 | 1200 | 1600 |
| <div style="display: flex; justify-content: space-around;"> <div style="text-align: center;"> <p>PK</p> </div> <div style="text-align: center;"> <p>PD</p> </div> </div> | 25  | 25GB |     | 25HB |      |
| <div style="display: flex; justify-content: space-around;"> <div style="text-align: center;"> <p>PE</p> </div> <div style="text-align: center;"> <p>KK</p> </div> </div> | 55  | 55GB |     | 55HB |      |
|  | 90  | 90GB |     | 90HB |      |

### Definitions of terms and symbols used Thyristor

| Symbol              | Term  | Definition   |
|---------------------|---|--|
| $V_{RRM}(V)$        | Repetitive Peak reverse Voltage               | The maximum reverse instantaneous recurrent voltage at which a thyristor will operate in the switching quadrants; the value is specified with the gate open.   |
| $V_{RSM}(V)$        | Non Repetitive Peak Reverse Voltage           | The maximum instantaneous transient voltage at which a thyristor will operate in the noise.  |
| $V_{DRM}(V)$        | Repetitive Peak off-state Voltage             | The maximum forward instantaneous recurrent voltage at which a thyristor will operate in the switching quadrants; the value is specified with the gate open.   |
| $I_{T(AV)}(A)$      | The average sinewave on-state current         | The maximum average on-state current at which the thyristor will operate at a specified referenced temperature. For reverse blocking and conducting thyristors this value is specified for 180° conduction angle.  |
| $I_{T(RMS)}(A)$     | R.M.S on-state current                        | The maximum RMS(on-state) current at which a thyristor will operate at a specific referenced temperature. This value is specified for 180° conduction angle.   |
| $I_{TSM}(A)$        | Surge on-state current                        | The non-repetitive current rating of the thyristor; measured at 25°C. This value is measured with one-half cycle sinewave current. This surge on state current shall be kept less than 100 times during serviceable life of device will destroyed.   |
| $I^2t(A^2 \cdot S)$ | $I^2t$ value for fusing                       | In the event that a type of overload or short circuit can be classified as non-recurrent, the rated junction temperature can be exceeded for a brief instant, thereby allowing additional overcurrent rating. Rating of nonrecurrent duty are given by the Surge Current and $I^2t$ rating.  |
| $P_{GM}(W)$         | Peak gate power dissipation                   | Repetitive peak gate power dissipation: allowable maximum value gate to Cathode.   |
| $P_{G(AV)}(W)$      | Average gate power dissipation                | Average gate power dissipation: allowable average value gate to cathode.   |
| $I_{FGM}(A)$        | Peak gate current                             | Repetitive peak gate current, allowable maximum value, gate to cathode.  |
| $V_{FGM}(V)$        | Peak gate voltage                             | Repetitive peak gate voltage, allowable maximum value, gate to cathode.  |
| $V_{RGM}(V)$        | Peak reverse gate voltage                     | Repetitive peak reverse gate voltage, allowable maximum value, cathode to gate.  |
| $di/dt(A/\mu s)$    | Critical rate of rise of on-state current     | The maximum rate of current rise which a thyristor can withstand without being damaged. Local "hot spot" heating will occur due to high current density in junction regions that have started to conduct.  |
| $T_J(°C)$           | Junction temperature                          | Temperature at junction during operation, and the same of pellet in device shall be regulated at upper and lower limit in an allowable range. The device will break due to difference of thermal expansion between silicon and molybdenum and copper anode in lower temperature. In higher temperature, thermal runaway lack of stability in silicon passivation, and deterioration in various characteristics will occur. |
| $I_{DRM}(mA)$       | Repetitive peak off-state and reverse current | Peak value of the leakage current at the state of gate open. Measured at $V_{DRM}$ , and $V_{RRM}$ , gate open.  |
| $I_{RRM}$           | Repetitive peak reverse current               | Peak value of the leakage current at the state of gate open. Measured at $V_{DRM}$ , and $V_{RRM}$ , gate open.  |
| $V_{TM}(V)$         | On-state voltage                              | The principle voltage between anode and cathode, measured at a specified current at 25°C. This measurement is determined with a instantaneous sinewave current with the peak values indicated.<br>$V_{TM}$ is measured by following equation. $V_{TM} = \pi \times I_{T(AV)}$  |
| $I_{GT}(mA)$        | Gate trigger current                          | The maximum gate current required to switch a thyristor to the on-state; usually measured at 25°C.   |
| $V_{GT}(V)$         | Gate trigger voltage                          | The voltage required to switch a thyristor to the on-state measured at 25°C.   |
| $V_{GQ}(V)$         | Non-trigger gate voltage                      | Maximum trigger voltage that thyristor will not turn on.   |
| $t_{GT}(\mu sec)$   | Turn-on time                                  | The time required to turn on a power thyristor measured at a specified current from a point on the gate pulse front, to a point on the main current or voltage pulse front, during the interval the thyristor is turning on; measured at 25°C.   |
| $dv/dt(V/\mu s)$    | Critical rate of rise of off-state voltage    | The minimum rate of rise of the main voltage which will switch the thyristor on. The rating covers the case of initially operating the device from an anode voltage source which has superposed fast rise-time transients. Static $dv/dt$ capability is an inverse function of device junction temperature as well as a complex function of the transient waveform.  |
| $I_H(mA)$           | Holding current                               | The current required to sustain conduction of the thyristor in the on-state; measured at 25°C.   |
| $I_L(mA)$           | Latching current                              | The current required to sustain conduction in the on-state immediately after the device has been switched to the on-state and the gate voltage removed.  |
| $R_{th}(°C/Watt)$   | Thermal impedance                             | Normal thermal impedance junction to case.   |